

Soft X-ray microscopy on a Lithium Fluoride-based novel imaging detector

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- Soft X-ray microscopy:
- \checkmark Configurations
- ✓ Water and carbon window
- \checkmark Standard imaging detectors

 Proposal:
 Single-shot Contact Soft X-ray microscopy on a Lithium Fluoride-based novel imaging detector
 Single Shot X-ray holography with coherent X-FEL radiation on LiF detector

- Biological images on LiF detector
- Conclusions

Soft X-ray microscopy

Traditional technique for biological samples imaging

Light Microscopy (LM)

Limitation: resolution limit due to the wavelength of visible light

Electron Microscopy (SEM or TEM) Limitation: preliminary treatments of sample (dehydration, fixing and dying with electron dense substances)

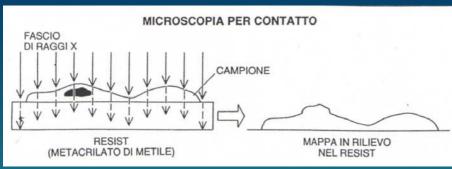
Soft X-Ray Microscopy ($\lambda > 1$ nm , E < 1 keV)

were introduced for imaging of internal structure of biological samples in their normal living state, at a high spatial resolution and avoiding all specimen preparation

X-ray sources for Soft X-ray microscopy:

Synchrotrons Laser Plasma Sources Micropinch discharges

X-ray microscopy configurations

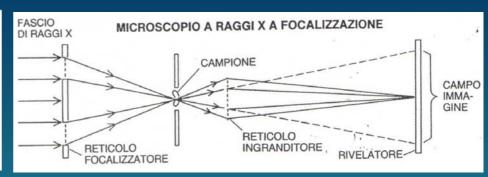


- No need of optical elements
- No coherent radiation

DI

 Imaging of biological samples in their living state in single shot exposure

• Spatial resolution limited by: diffraction effect, penumbra blurring, detector.



- Need of optical elements
- Need of monochromatic radiation

·Imaging of biological samples in their living state in single shot exposure only with high intensity sources.

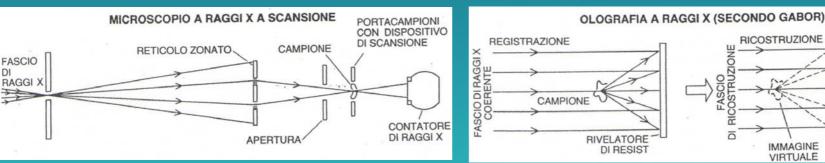
OLO-

GRAMMA

>IMMA-

GINE

REALE



Scanning X-ray microscopy:

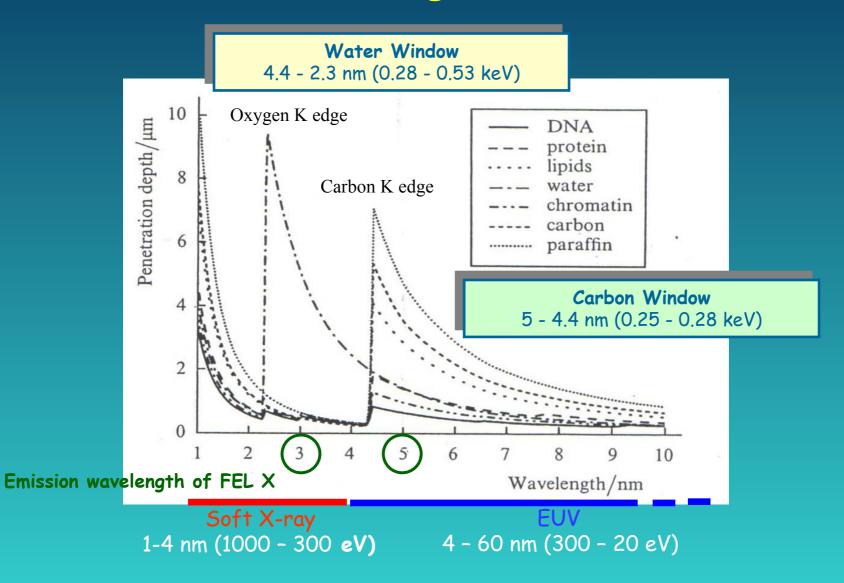
- Need of optical elements
- Need of monochromatic radiation
- Need of long exposure time

Holography:

Need of coherent radiation

• Imaging of biological samples in their living state in single shot exposure only with high intensity coherent sources.

Penetration depth in water and in biological material



Imaging detectors for Soft X-ray Microscopy

Photographic film

Pixel size ~ 5 μ m Fluence dynamic range: 1 nJ/cm² - 1 μ J/cm² Readout system: optical microscope

CCD (Charge Coupled Devices)

Pixel size ~ 2 μ m Fluence dynamic range: 0.1 nJ/cm² - 10 μ J/cm² Readout system: Analogical/Digital Conversion

Photoresist PMMA

Pixel size ~ 0.01 μm Fluence dynamic range: 1 mJ/cm² - 50 mJ/cm² Readout system: Atomic Force microscope

Innovative imaging detector based on Optically Stimulated Luminescence (OSL) of color centers in Lithium Fluoride (LiF): high spatial resolution, high dynamic range, efficient detection and redout process.

Single-shot Contact Soft X-ray microscopy on a Lithium Fluoride-based novel imaging detector

X-FEL	 Contact X-ray microscopy: No need of optical elements No coherent radiation Imaging of biological samples in their living state in single shot exposure Spatial resolution limited by: diffraction effect ((λ×d)^{1/2}), penumbra blurring (P = S×d/D), detector. 	
Detector Lithium Fluoride film	Peculiarity of SPARX source \odot High Brightness: 3-8×10 ³⁰ Phot/s/0.1%bw/(mm-mrad) ² \odot Short duration: ~ 100 fs $\odot \lambda$ = 3-5 nm (water and carbon window)	

The peculiarity of SPARX source allows to obtain images of biological samples with very high spatial and time resolution.

The high brightness and the short duration allows to obtain images:

• in a single shot of living biological samples. The short duration allows to study living biological specimens in a very short exposure time, before radiation damage occurs. The fs-FEL pulse allows a high time resolution.

with very high spatial resolution

LiF-based soft X-ray detector could fully exploit the potentiality offered by SPARX peculiar characterisitcs.

X-ray fluence vs spatial resolution

F= source fluence μ = absorption coefficient

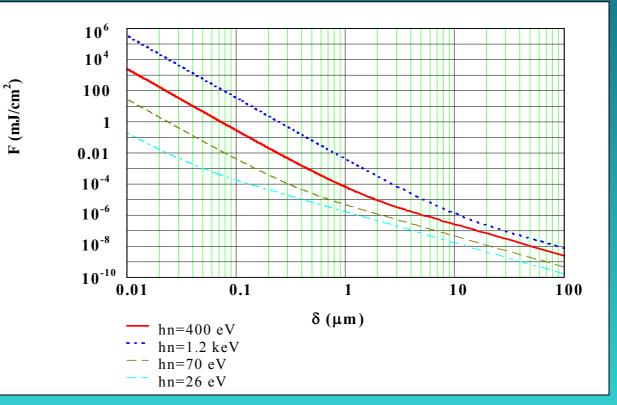
 $N_0 = \delta^2 \cdot F / h\nu$ $N_1 = \delta^2 \cdot F \cdot e^{-\mu\delta} / h\nu$

Condition to see the shadow

$$N_1 - N_0 \ge 2\sqrt{N_1} + 2\sqrt{N_0}$$

from which:

$$F = h\nu \cdot \frac{4}{\delta^2} \cdot \left(\frac{1 + \sqrt{e^{-\mu\delta}}}{1 - e^{-\mu\delta}}\right)^2$$



δ

N1

X-rays

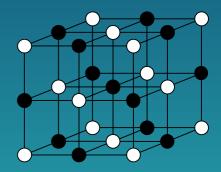
A novel imaging detector for Soft X-ray Microscopy based on LiF

We propose to use a novel X-ray imaging detector based on optically stimulated luminescence (OSL) of color centers in Lithium Fluoride (LiF)

<u>Alkali halides</u>: ionic crystals with face centered cubic structure, optically transparent from near UV to IR

LiF is of particular interest because : •it is almost *non-hygroscopic* •it can host point defects *stable at room temperature* •it can host *laser active color centers* tunable in a broad wavelength range in the *VIS* and *NIR*.

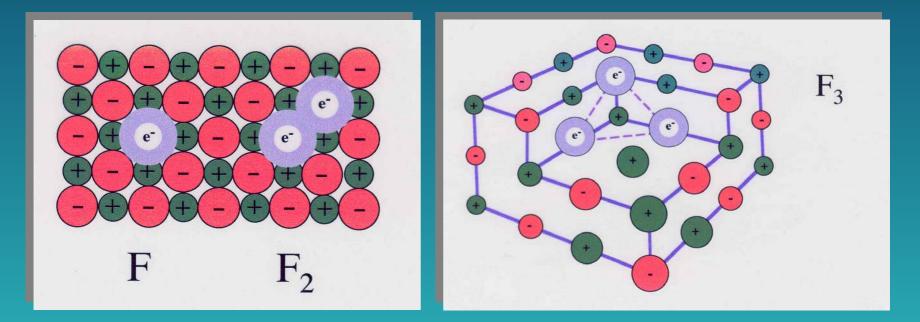
Polycrystalline LiF films can be grown by thermal evaporation on different substrates



Nearest neighbour distance (Å)	2.013
Melting point (°C)	848.2
Density (g/cm³)	2.640
Molecular weight	25.939
Refractive index @ 640 nm, RT	1.3912
Solubility (g/100g H ₂ O @ 25°C)	0.134
Transmission range (µm)	0.12 - 7

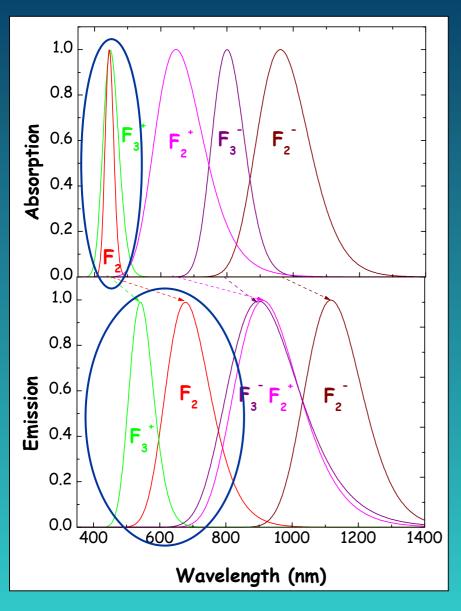
Color centers in LiF

Optically active defects in LiF can be generated by ionizing radiation like charged particles (electrons and ions), as well as gamma and X-rays.



F center is an anion vacancy occupied by an electron; they are not optically active centers active centers F_2 and F_3^+ centers are optically active F-aggregates consisting in two electrons bound to two and three close anion vacancies, respectively

Laser active in LiF at RT



Center	Ea, eV,nm	Ee, eV,nm	HWa, eV	HWe, eV
F	5.00, 248	-	0.76	
F ₂	2.78, 445	1.85, 670	0.186	0.279
F ₃ ⁺	2.70, 458	2.30, 539	0.347	0.347
F ₂ ⁺	1.97, 630	1.36, 910	0.434	0.29
F ₂ -	1.29, 960	1.1, 1120	0.21	0.17
F ₃ (R ₁)	3.92, 316			
F ₃ (R ₂)	3.31, 374			
F ₄ (N ₁)	2.40, 517			
F ₄ (N ₂)	2.26, 547			
Li colloids	2.75, 450			

Miniaturized photonic devices based on CCs in LiF by using Electron Beam Litography

The use of versatile, well-assessed and low-cost fabrication techinques consisting of physical vapor deposition of LiF films combined with direct writing lithographic processes based on electron-beam allows the realization of miniaturized optical structures, like:



F. Bonfigli, B. Jacquier, F. Menchini, R.M. Montereali, P. Moretti, E. Nichelatti, M. Piccinini, H. Rigneault, F. Somma Radiation Effects & Defects in Solids, Vol. 158, 185-190 (2003).

R.M. Montereali, A. Mancini, G.C. Righini, S. Pelli, Opt. Commun. 153, 223 (1998). F. Bonfigli, S. Loreti, T. Marolo, R.M. Montereali, A. Pace, A. Santoni, M. Piccinini, S. Sekatskii, Abstracts Nanocose 2, Frascati (Roma), 13-15 Ottobre 2003, p.25.

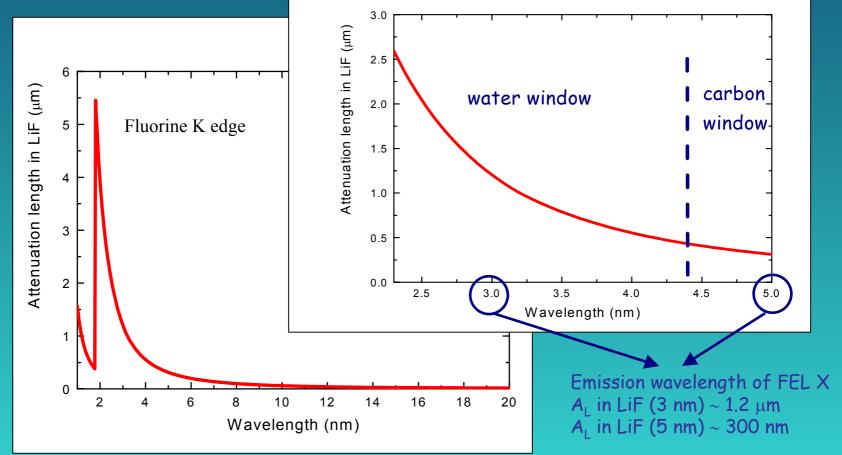
Peculiarity of soft X-rays in LiF coloration

Short wavelength

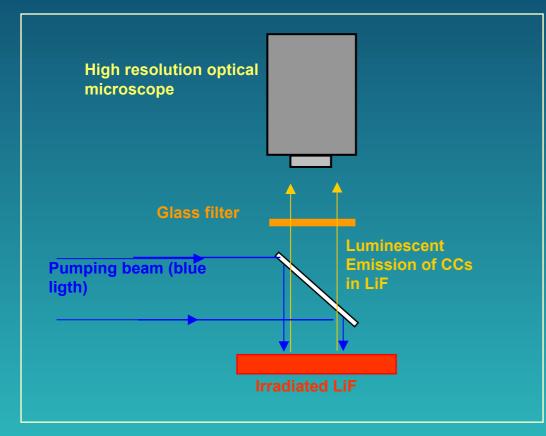
Neutrality

formation of active color centers with high spatial resolution

Low penetration depth



Readout process of Optically Stimulated Luminescence (OSL) from Lithium Fluoride detector



Images stored in the irradiated LiF samples are observed by using optical microscopes in fluorescent mode. Irradiation with blue light excites the visible photoluminescence of the F_2 and F_3^+ defects locally created in the areas previously exposed to the X-ray beam.

With appropriate laser excitation sources and time-resolved detection, the luminescence sensitivity maybe virtually unlimited: under suitable conditions even single luminescence center present in the sample can be detected.

Lithium Fluoride-based novel imaging detector

LiF detector Pixel size ~ 0.001 µm Fluence dynamic range: 0.1 mJ/cm² – 1 J/cm² Readout system: advanced optical fluorescence microscope

CCD (Charge Coupled Devices)

Pixel size ~ 2 μ m Fluence dynamic range: 0.1 nJ/cm² - 10 μ J/cm² Readout system: Analogical/Digital Conversion

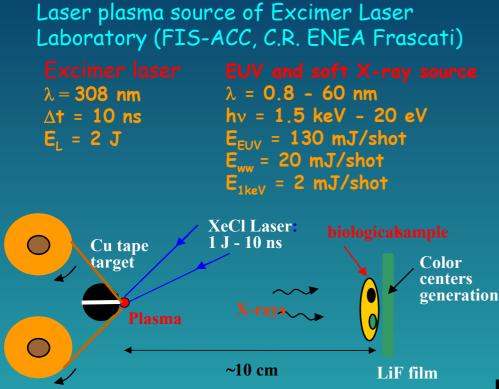
Photographic film

Pixel size ~ 5 μ m Fluence dynamic range: 1 nJ/cm² - 1 μ J/cm² Readout system: optical microscope

Photoresist PMMA

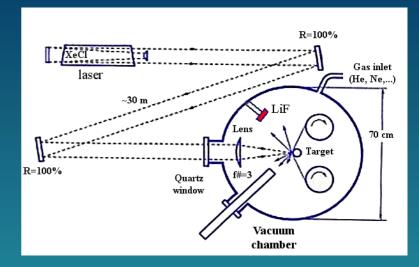
Pixel size ~ 0.01 μm Fluence dynamic range: 1 mJ/cm² - 50 mJ/cm² Readout system: Atomic Force microscope

Micro-radiography of a dragonfly (Pyrrhesoma nymphula) wing on LiF



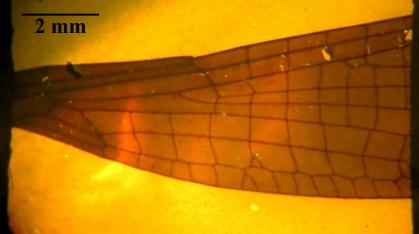
Wing micro-radiography on 2 μm thick LiF film at optical microscope obtained by observing the Optically Stimulated Luminescence (OSL). Pumping wavelength: 458 nm

ENEA patent n° TO2002A000575

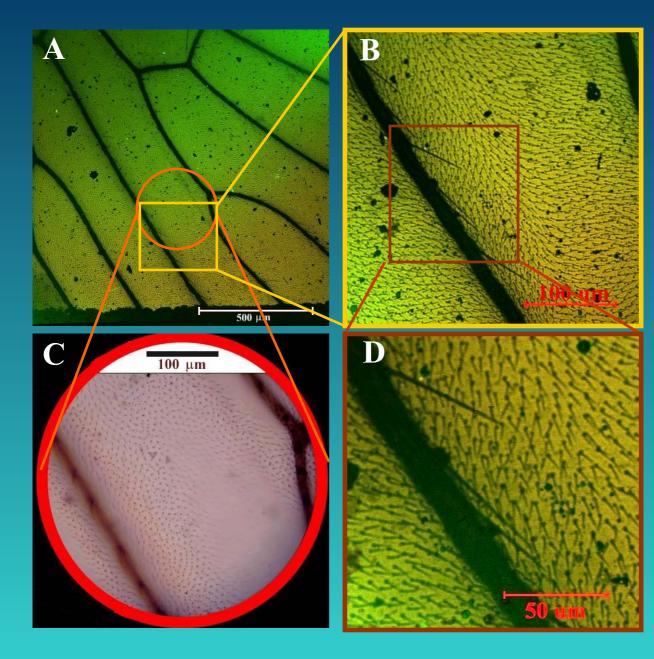


Biological sample: dragonfly (*Pyrrhesoma nymphula*) wing

LiF sample: 2 μm film, thermally evaporated on glass



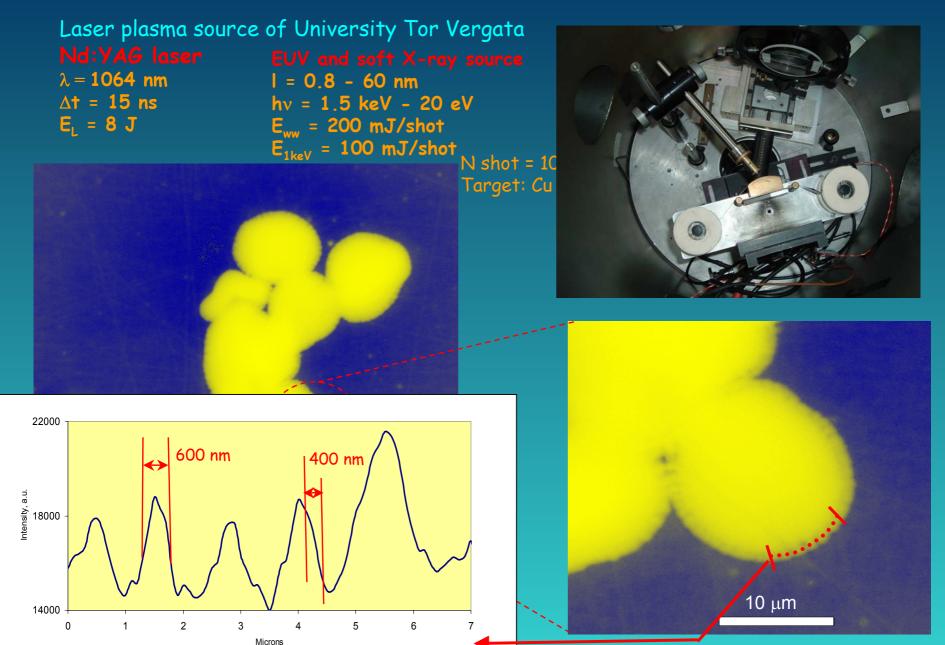
Micro-radiography of a mosquito (Diptera) wing on LiF



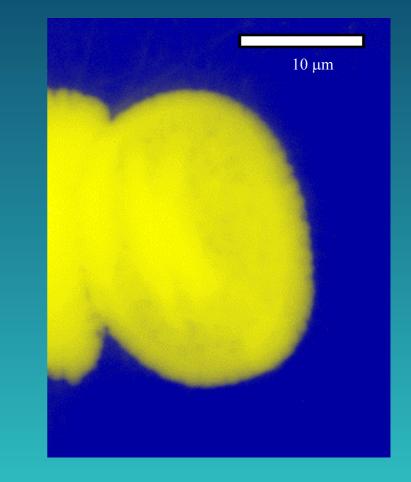
A, B, D: Wing radiograph stored on a LiF film (120 nm) and observed under a ZEISS LSM 510 fluorescence confocal optical microscope at different magnification values

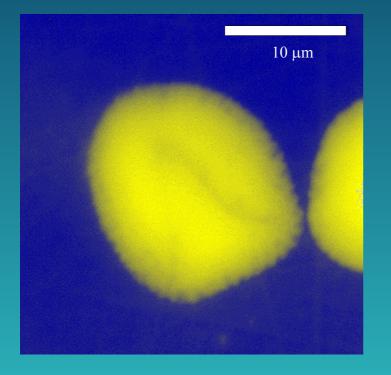
C: Image of the same wing, directly observed under a conventional optical microscope in transmission mode

Micro-radiography of a Lylium pollen on LiF



Micro-radiography of a Lylium pollen on LiF

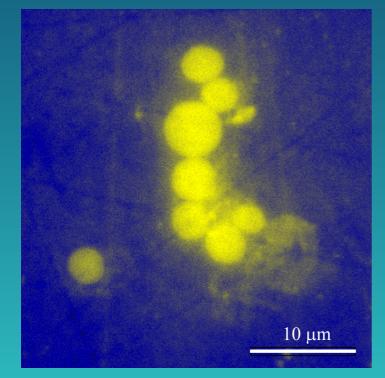


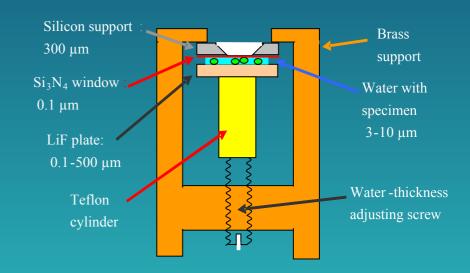


Microscopy of chlorella cells

Laser plasma source of University Tor VergataNd: YAG laserEUV and soft X-ray source $\lambda = 1064 \text{ nm}$ I = 0.8 - 60 nm $\Delta t = 15 \text{ ns}$ hv = 1.5 keV - 20 eV $E_L = 8 \text{ J}$ $E_{ww} = 200 \text{ mJ/shot}$ $E_{IVAV} = 100 \text{ mJ/shot}$

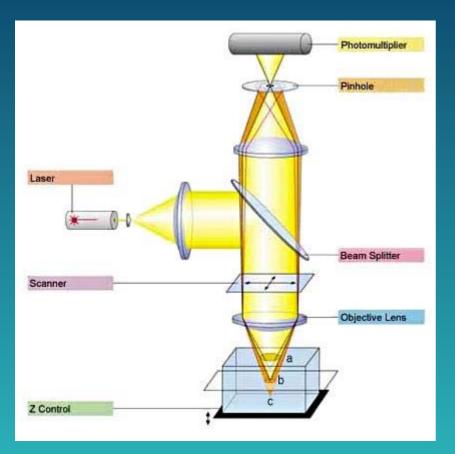
N shot = 1 Target = Y LiF Protection layer - Benzene



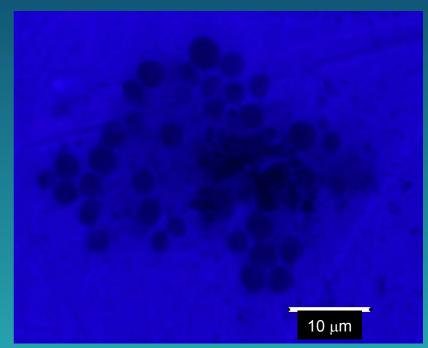


Chlorella cells image on a LiF crystal at optical microscope obtained by observing the Optically Stimulated Luminescence (OSL).

Confocal Laser Scanning Microscope (CLSM)



Only in-focus light (b) arrives at the detector; all out-of-focus light (a,c) is eliminated.



Chlorella cells image on a LiF crystal at CLSM obtained by observing the Optically Stimulated Luminescence (OSL). Pumping wavelength: 458 nm

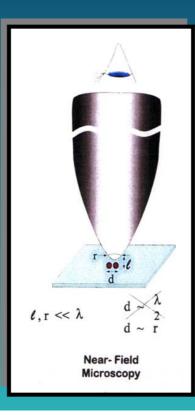
Advanced Optical Microscope

Near-field microscopy

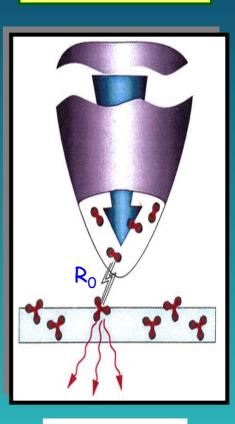
Conventional Far-field microscopy

$d \sim \frac{\lambda}{2}$ Conventional Far-field microscopy

Spatial resolution: ~ 250-300 nm



Spatial resolution: ~ 20-50 nm

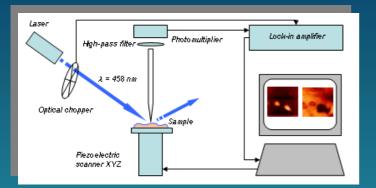


FRET SNOM

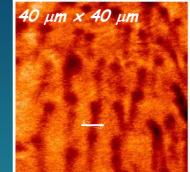
$R_0 \sim 1-5 \text{ nm}$

S.K. Sekatskii, V.S. Letokhov, *JEPT Lett.* 63, 319 (1996)

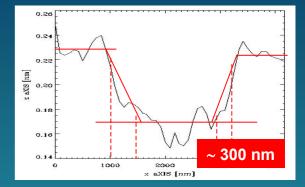
Scanning Near Field Microscope (SNOM) observation

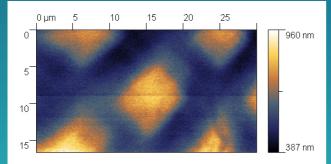


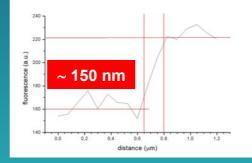
Regular luminescent pattern on LiF

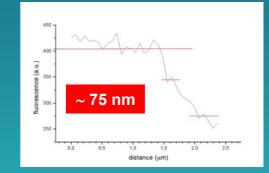


Wing micro-radiography on LiF

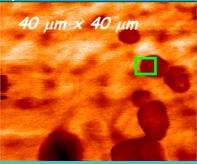


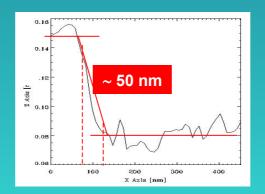






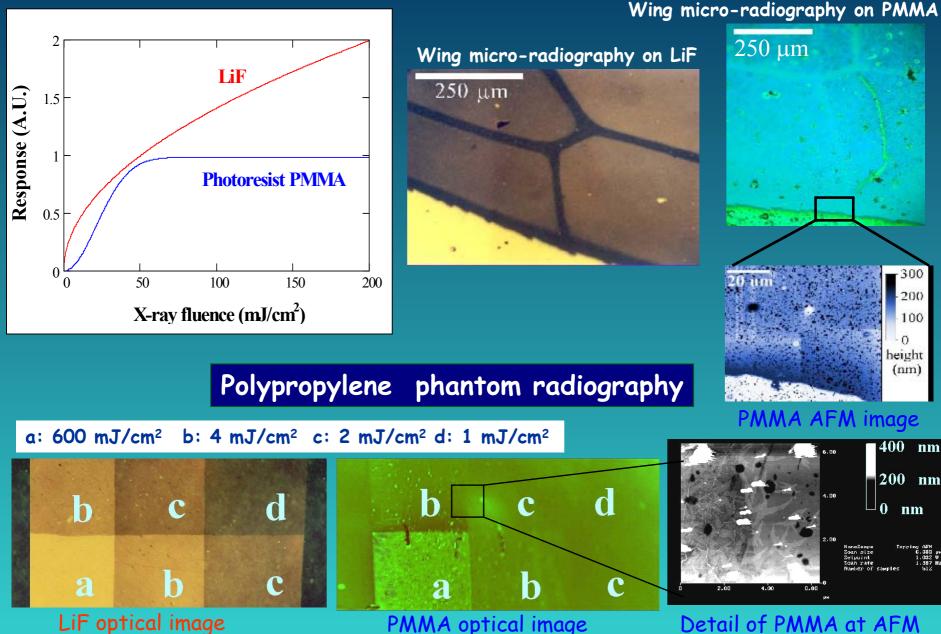
Laser plasma source debris on LiF





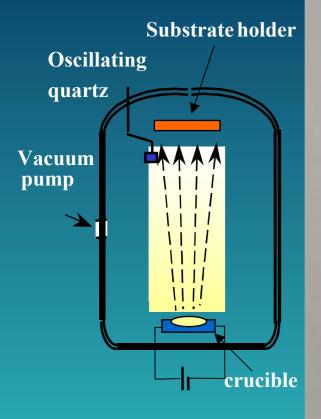
Courtesy of Dr. A. Cricenti , A. Ustione CNR-ISM Tor Vergata

Dynamic range of LiF detector and of Photoresist



Detail of PMMA at AFM

LiF film deposition by physical vapour deposition





Solid State Laser Laboratory (C.R. ENEA Frascati)

UTS FIS-ACC ENEA C.R. Frascati, Via Enrico Fermi, 27, 00044 Frascati (Rome). Italy Tel: +39 0694005567

5.0 mm x 5.0 mm silicon chips coated with 3µm LiF

3 μm thick LiF film on (5x5) mm² Si substrate produced by Solid State Laser Lab

Fabrication Services & Technology Ltd

JBJ Business Park, Northampton Road, Blisworth, Northampton, NN7 3DW. England Tel: +44 1604 859996 Fax: +44 1604 859991

5.0 mm x 5.0 mm silicon chips coated with 495K PMMA

FaSTec Ref: #19801101 Customer Ref: #ENEA0137 Purchase Order No: PE 28994

Commercial 0.5 μ m thick PMMA film on (5x5) mm² Si substrate

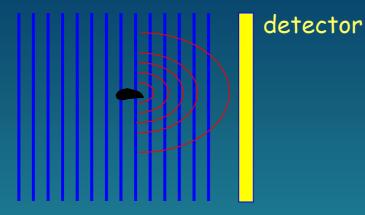
Deposition parameters

Pressure P < 10-6 mbar Evaporation rate R = 0.5-2 nm/s Total film thickness t = 5 nm - 5 μm Substrate temperature Ts = 250 °C

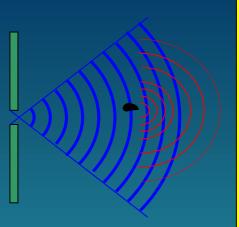




X-ray holography with coherent radiation Gabor in-line holography



The reference beam is a plane wave.
No need of optical elements
The detector must have a good spatial resolution.

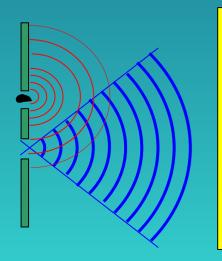


detector

- •The reference beam is a spherical wave
- •Need of optical elements
- •The detector's spatial resolution is not crucial.

Fourier Transform holography

detector

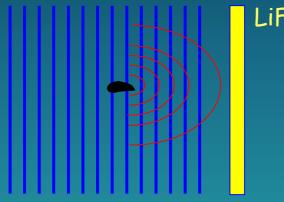


The reference beam (spherical wave) is placed in the same plane as the object
Need of optical elements

The resolution of the reconstructured images depends on the information recorded in the hologram which is limited by thesize of the detector and its resolution

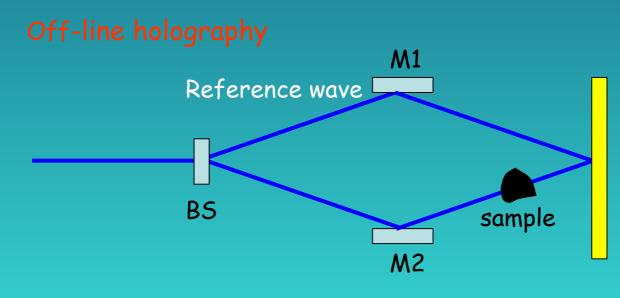
Single Shot X-ray holography with coherent X-FEL radiation on LiF detector

Gabor in-line holography



LiF detector

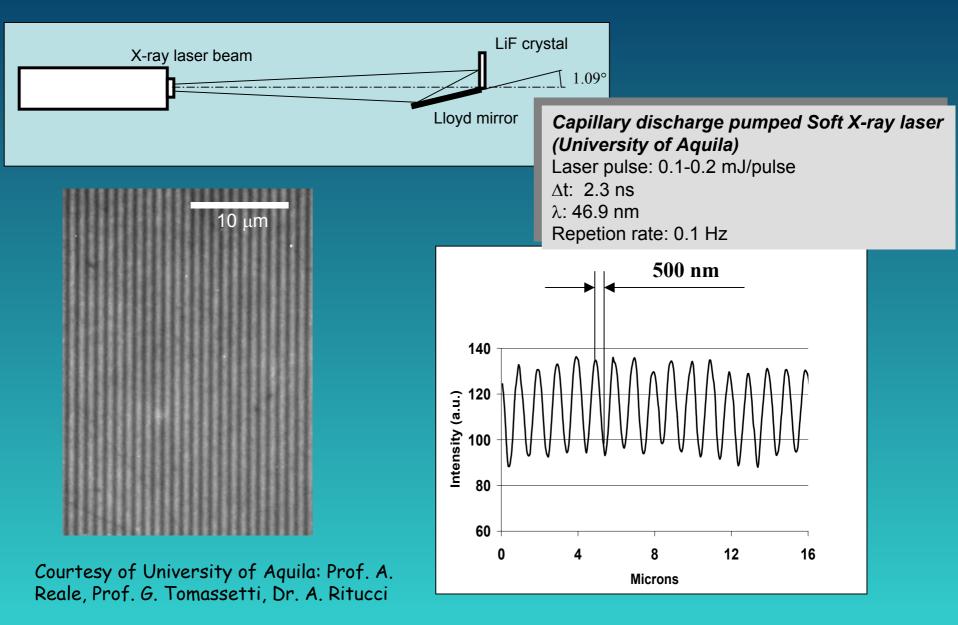
Combining the coherence $(30-45 \ \mu m)$ of the X FEL beam and the peculiarity of the LiF detector (spatial resolution and dynamic range) fine fringes can be stored in the hologram plane and a high spatially reconstructed images can be obtained in a single shot experiment

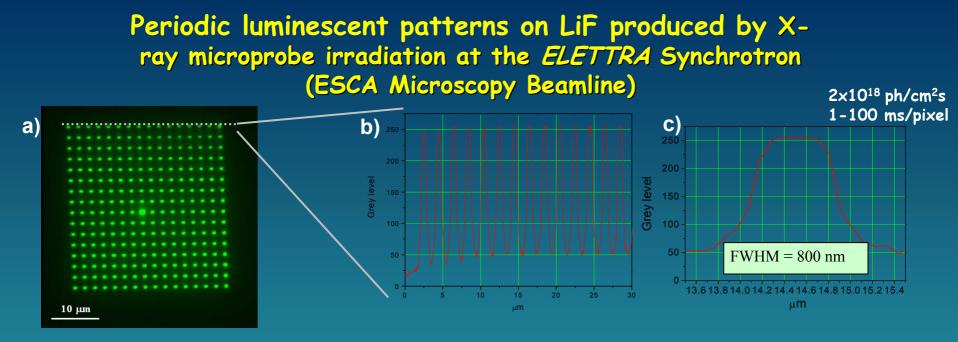


LiF detector

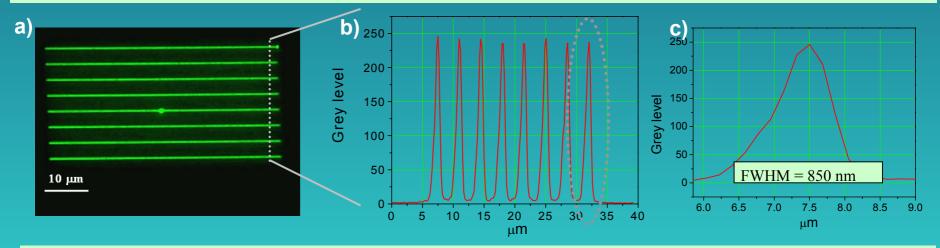
Due to the coherence of the beam, more complex holographic circuit can be proposed.

Interferometric pattern on LiF by capillary discharge pumped soft X-ray laser





A typical fluorescent grating based on CCs directly written on a 324 nm thick LiF film on Si, E=450eV. CLSM (Nikon) image a), its intensity profile, b) and detail of a single line, c).



Fluorescence microscope (Leica) images of a regular array (32x32) μ m² of 16x16 dots 2.0 μ m spaced, realized on 324 nm thick LiF film on Si, a), its intensity profile, b) and detail of a single line, c).

CONCLUSIONS

We presented a proposal for exploiting the soft X-ray radiation produced by SPARX in the field of biological investigation by using single-shot contact microscopy and holography on an innovative imaging detector based on OSL of CCs in LiF.

The high brightness and short duration of SPARX source could allow to obtain imaging of biological specimens in their living state with very high spatial and time resolution. Due the coherence of X FEL beam, biological investigation can be performed by single shot holography experiments as a method for a high resolution 3D imaging, also with complex holographic circuits.

A LiF-based soft X-ray imaging sensor could overcome the limitations of the standard detectors and fully exploit the potentialities offered by SPARX peculiar charactestics.

LiF detector peculiarities

- •High dynamic range (10-12 bits)
- High resolution
- Efficient detection and readout process (OSL)
- Large field of view
- No development needs
- Compatible with permanent protective layers